

<b>Issue Classification</b> 			Application/Control No.		Applicant(s)/Patent under Reexamination	
			10/020,926		CHEN ET AL.	
			Examiner		Art Unit	
			Yuwen Pan		2618	

ORIGINAL			CROSS REFERENCE(S)							
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
455	452.2	455	450	452.1	453	455	509	512	513	
INTERNATIONAL CLASSIFICATION			516	517	525	631	456.1	456.2		
H 04 Q	7 120									
H 04 B	7 100									
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<i>Yueh 7/07/06</i> (Assistant Examiner) (Date)			<i>M. Anderson</i> Matthew D. Anderson Supervisory Patent Examiner (Primary Examiner) (Date) 7/6/06							
<i>D. L. Smith 7/10/06</i> (Legal Instruments Examiner) (Date)										
Total Claims Allowed: 16 O.G. Print Claim(s) 21 O.G. Print Fig. 4										

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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5	5	13	35	65	95	125	155
6	6	19	36	66	96	126	156
7	7	15	37	67	97	127	157
8	8	16	38	68	98	128	158
9	9	39	69	99	129	129	159
10	10	40	70	100	130	160	190
11	11	41	71	101	131	161	191
12	12	42	72	102	132	162	192
13	13	43	73	103	133	163	193
14	14	44	74	104	134	164	194
15	15	45	75	105	135	165	195
16	16	46	76	106	136	166	196
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19	19	49	79	109	139	169	199
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26	26	56	86	116	146	176	206
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